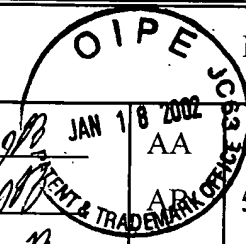


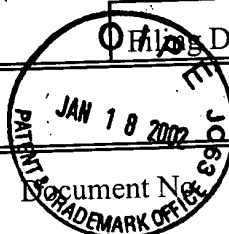
INFORMATION DISCLOSURE CITATION PTO-1449	Atty. Docket No. 010816	Serial No. 09/891,612
	Applicant: Mamoru NAKASUJI et al.	
	Filing Date: June 27, 2001	Group Art Unit:

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		Document No.	Date	Country	Translation (Yes or No)
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	AB	52-117567✓	10/03/77	JAPAN	ABSTRACT
	AC	57-072326✓	05/06/82	JAPAN	ABSTRACT
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	AR	10-062503✓	03/06/98	JAPAN	ABSTRACT
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	AU	2000-090868✓	03/31/00	JAPAN	ABSTRACT
	AV	07-249393✓	09/26/95	JAPAN	ABSTRACT

Examiner <i>Jack Berman</i>	Date Considered <i>5/29/03</i>
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	Applicant: Mamoru NAKASUJI et al.	
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<i>JPB</i>	AX	6,087,667	Nakasuji et al.	07/11/00		09/30/97
<i>JPB</i>	AY	5,994,704	Nakasuji	11/30/99		10/03/97
<i>JPB</i>	AZ	5,981,947	Nakasuji et al.	11/09/99		02/03/98
<i>JPB</i>	BA	5,892,224	Nakasuji	04/06/99		05/09/97
<i>JPB</i>	BC	5,770,863	Nakasuji	06/23/98		10/24/96
<i>JPB</i>	BD	5,763,893	Nakasuji	06/09/98		12/16/96
<i>JPB</i>	BE	5,751,538	Nakasuji	05/12/98		09/26/96
<i>JPB</i>	BF	5,747,819	Nakasuji et al.	05/05/98		10/30/96
<i>JPB</i>	BG	5,362,968	Miyoshi et al.	11/08/94		09/27/93
<i>JPB</i>	BH	5,359,197	Komatsu et al.	10/25/94		07/16/93
<i>JPB</i>	BI	4,912,052	Miyoshi et al.	03/27/90		09/23/88

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<i>JPB</i>	BJ	✓ Low Voltage and high speed operating electrostatic wafer chuck using sputtered tantalum oxide membrane, Mamoru Nakasuji et al., J. Vac. Sci. Technol. A 12(5), Sep/Oct 1994, American Vacuum Society pp. 2834-2839.
<i>JPB</i>	BK	✓ High -Emittance and Low-Brightness Electron Gun for Reducing-Image Projection System: Computer Simulation, Mamoru Nakasuji et al., Jpn. J. Appl. Phys. Vol. 36 (1997) pp.2404-2408.
<i>JPB</i>	BL	✓ H. Hayashi, et al., LSI Testing Symposium 1998, Minutes of the meeting, P160 (1998) (partial translation)
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	Applicant: Mamoru NAKASUJI et al.	
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<p><i>JP</i></p> <p><i>JP</i></p> <p><i>JP</i></p> <p><i>JP</i></p> <p>-----</p>	BM BN BO BP	<p>Multi-Beam Concepts for Nanometer Devices, B. Lischke et al., Japanese Journal of Applied Physics, Vol. 28, No.10, October 1989, pp. 2058-2064.</p> <p>An electron-beam inspecting system for x-ray mask production, P. Sandland et al., J. Vac. Sci. Technol. B9 (6), Nov/Dec. 1991, American Vacuum Society, pp.3005-3009.</p> <p>Requirements and performance of an electron-beam column designed for x-ray mask inspection, W.D. Meisburger et al., J. Vac. Sci. Technol. B9 (6), Nov/Dec 1991, American Vacuum Society, pp.3010-3014.</p> <p>Table 5-1 Work Function in Metals page 116.</p>
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**INFORMATION
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PTO-1449

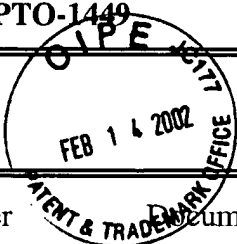
Atty. Docket No. 010816

Serial No. 09/891,612

Applicant(s): NAKASUJI, et al.

Filing Date: June 27, 2001

Group Art Unit: 2877



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